Intel - 5SGXEA7K2F40I3 Datasheet





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Details

Product Status	Obsolete
Number of LABs/CLBs	234720
Number of Logic Elements/Cells	622000
Total RAM Bits	51200000
Number of I/O	696
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxea7k2f40i3

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Table 5 lists the maximum allowed input overshoot voltage and the duration of the overshoot voltage as a percentage of device lifetime. The maximum allowed overshoot duration is specified as a percentage of high time over the lifetime of the device. A DC signal is equivalent to 100% of the duty cycle. For example, a signal that overshoots to 3.95 V can be at 3.95 V for only ~21% over the lifetime of the device; for a device lifetime of 10 years, the overshoot duration amounts to ~2 years.

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Symbol	Description	Condition (V)	Overshoot Duration as % @ T _J = 100°C	Unit							
		3.8	100	%							
		3.85	64	%							
		3.9	36	%							
		3.95	21	%							
Vi (AC)	AC input voltage	4	12	%							
		4.05	7	%							
		4.1	4	%							
		4.15	2	%							
		4.2	1	%							

Table 5. Maximum Allowed Overshoot During Transitions

Figure 1. Stratix V Device Overshoot Duration



Symbol	Description	Condition	Min ⁽⁴⁾	Тур	Max ⁽⁴⁾	Unit
t _{RAMP}	Power supply ramp time	Standard POR	200 µs	_	100 ms	—
		Fast POR	200 µs		4 ms	

Table 6. Recommended Operating Conditions for Stratix V Devices (Part 2 of 2)

Notes to Table 6:

(1) V_{CCPD} must be 2.5 V when V_{CCI0} is 2.5, 1.8, 1.5, 1.35, 1.25 or 1.2 V. V_{CCPD} must be 3.0 V when V_{CCI0} is 3.0 V.

(2) If you do not use the design security feature in Stratix V devices, connect V_{CCBAT} to a 1.2- to 3.0-V power supply. Stratix V power-on-reset (POR) circuitry monitors V_{CCBAT}. Stratix V devices will not exit POR if V_{CCBAT} stays at logic low.

(3) C2L and I2L can also be run at 0.90 V for legacy boards that were designed for the C2 and I2 speed grades.

(4) The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

Table 7 lists the transceiver power supply recommended operating conditions for Stratix V GX, GS, and GT devices.

Table 7. Recommended Transceiver Power Supply Operating Conditions for Stratix V GX, GS, and GT Devices (Part 1 of 2)

Symbol	Description	Devices	Minimum ⁽⁴⁾	Typical	Maximum ⁽⁴⁾	Unit
V _{CCA GXBL}	Transceiver channel PLL power supply (left		2.85	3.0	3.15	V
(1), (3)	side)	un, us, ui	2.375	2.5	2.625	v
V _{CCA_GXBR}	Transceiver channel PLL power supply (right	CV CS	2.85	3.0	3.15	V
(1), (3)	side)	ux, us	2.375	2.5	2.625	v
V _{CCA_GTBR}	Transceiver channel PLL power supply (right side)	GT	2.85	3.0	3.15	V
	Transceiver hard IP power supply (left side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
V _{CCHIP_L}	Transceiver hard IP power supply (left side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
	Transceiver hard IP power supply (right side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
V _{CCHIP_R}	Transceiver hard IP power supply (right side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
	Transceiver PCS power supply (left side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
V _{CCHSSI_L}	Transceiver PCS power supply (left side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
	Transceiver PCS power supply (right side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
V _{CCHSSI_R}	Transceiver PCS power supply (right side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
			0.82	0.85	0.88	
V _{CCR_GXBL}	Receiver analog nower supply (left side)	GX, GS, GT	0.87	0.90	0.93	V
(2) _	Therefore analog power supply (left Slue)		0.97	1.0	1.03	
			1.03	1.05	1.07	

			Resistance Tolerance				
Symbol	Description	Conditions	C1	C2,I2	C3, I3, I3YY	C4, I4	Unit
50-Ω R _S	Internal series termination without calibration (50- Ω setting)	$V_{CCIO} = 1.8$ and 1.5 V	±30	±30	±40	±40	%
50-Ω R _S	Internal series termination without calibration (50- Ω setting)	V _{CCI0} = 1.2 V	±35	±35	±50	±50	%
100-Ω R _D	Internal differential termination (100- Ω setting)	V _{CCPD} = 2.5 V	±25	±25	±25	±25	%

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 2 of 2)

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

Equation 1. OCT Variation Without Recalibration for Stratix V Devices (1), (2), (3), (4), (5), (6)

$$R_{OCT} \,=\, R_{SCAL} \Big(1 + \langle \frac{dR}{dT} \times \Delta T \rangle \pm \langle \frac{dR}{dV} \times \Delta V \rangle \Big) \label{eq:ROCT}$$

Notes to Equation 1:

- (1) The R_{OCT} value shows the range of OCT resistance with the variation of temperature and V_{CCIO} .
- (2) R_{SCAL} is the OCT resistance value at power-up.
- (3) ΔT is the variation of temperature with respect to the temperature at power-up.
- (4) ΔV is the variation of voltage with respect to the V_{CCIO} at power-up.
- (5) dR/dT is the percentage change of R_{SCAL} with temperature.
- (6) dR/dV is the percentage change of $\mathsf{R}_{\mathsf{SCAL}}$ with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 1 of 2)
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Symbol	Description	V _{CCIO} (V)	Typical	Unit	
dR/dV		3.0	0.0297		
	OCT variation with voltage without recalibration	2.5	0.0344		
		1.8	0.0499	%/mV	
		1.5	0.0744		
		1.2	0.1241		

Switching Characteristics

This section provides performance characteristics of the Stratix V core and periphery blocks.

These characteristics can be designated as Preliminary or Final.

- Preliminary characteristics are created using simulation results, process data, and other known parameters. The title of these tables show the designation as "Preliminary."
- Final numbers are based on actual silicon characterization and testing. The numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions. There are no designations on finalized tables.

Transceiver Performance Specifications

This section describes transceiver performance specifications.

Table 23 lists the Stratix V GX and GS transceiver specifications.

Table 23.	Transceiver 3	Specifications	for Stratix	V GX	and GS	Devices	(1)	(Part 1	nf 7	۱
Table 20.	TIANSUCIACI	opeonitionationa	IUI UIIAIIA	I UA	anu uu	DEVICES	• •	(1 61 6 1		

Symbol/	Conditions	Transceiver Speed Grade 1		Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit		
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max		
Reference Clock												
Supported I/O	PCML,	1.4-V PCM	IL, 1.5-∖	/ PCML	, 2.5-V PCN HCSL	1L, Diffe	rential	LVPECL, L\	/DS, and			
Standards	RX reference clock pin		1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS									
Input Reference Clock Frequency (CMU PLL) ⁽⁸⁾	_	40		710	40	_	710	40	_	710	MHz	
Input Reference Clock Frequency (ATX PLL) ⁽⁸⁾		100		710	100		710	100	_	710	MHz	
Rise time	Measure at ±60 mV of differential signal ⁽²⁶⁾			400	_		400			400	ns	
Fall time	Measure at ±60 mV of differential signal ⁽²⁶⁾		_	400	_		400			400	ps	
Duty cycle		45		55	45		55	45	—	55	%	
Spread-spectrum modulating clock frequency	PCI Express® (PCIe [®])	30		33	30		33	30	_	33	kHz	

Symbol/	Conditions	Trai	nsceive Grade	r Speed 1	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	-
	DC Gain Setting = 0		0	_	_	0	_	_	0	—	dB
	DC Gain Setting = 1	_	2		_	2	_	_	2	_	dB
Programmable DC gain	DC Gain Setting = 2	_	4	_	_	4	_	_	4	_	dB
	DC Gain Setting = 3	_	6	_	_	6	_	_	6	_	dB
	DC Gain Setting = 4		8			8	—		8	_	dB
Transmitter											
Supported I/O Standards	_		1.4-V and 1.5-V PCML								
Data rate (Standard PCS)	_	600	_	12200	600	_	12200	600	_	8500/ 10312.5 (24)	Mbps
Data rate (10G PCS)	_	600	_	14100	600	_	12500	600	_	8500/ 10312.5 (24)	Mbps
	85-Ω setting	_	85 ± 20%	_	_	85 ± 20%	_	_	85 ± 20%	—	Ω
Differential on-	100-Ω setting	_	100 ± 20%	_	_	100 ± 20%	_	_	100 ± 20%	_	Ω
chip termination resistors	120-Ω setting		120 ± 20%	_		120 ± 20%	_		120 ± 20%	_	Ω
	150-Ω setting	_	150 ± 20%			150 ± 20%	_		150 ± 20%	_	Ω
V _{OCM} (AC coupled)	0.65-V setting	_	650		_	650	_	_	650	—	mV
V _{OCM} (DC coupled)	_	_	650	_	_	650		_	650	_	mV
Rise time ⁽⁷⁾	20% to 80%	30	—	160	30	—	160	30	—	160	ps
Fall time ⁽⁷⁾	80% to 20%	30		160	30		160	30	—	160	ps
Intra-differential pair skew	Tx V _{CM} = 0.5 V and slew rate of 15 ps	_	_	15			15		_	15	ps
Intra-transceiver block transmitter channel-to- channel skew	x6 PMA bonded mode	_	_	120	_	_	120	_		120	ps

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 5 of 7)

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
t _{pll_lock} (16)	_			10			10		_	10	μs

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 7 of 7)

Notes to Table 23:

(2) The reference clock common mode voltage is equal to the V_{CCR_GXB} power supply level.

(3) This supply must be connected to 1.0 V if the transceiver is configured at a data rate > 6.5 Gbps, and to 1.05 V if configured at a data rate > 10.3 Gbps when DFE is used. For data rates up to 6.5 Gbps, you can connect this supply to 0.85 V.

- (4) This supply follows VCCR_GXB.
- (5) The device cannot tolerate prolonged operation at this absolute maximum.
- (6) The differential eye opening specification at the receiver input pins assumes that **Receiver Equalization** is disabled. If you enable **Receiver Equalization**, the receiver circuitry can tolerate a lower minimum eye opening, depending on the equalization level.
- (7) The Quartus II software automatically selects the appropriate slew rate depending on the configured data rate or functional mode.
- (8) The input reference clock frequency options depend on the data rate and the device speed grade.
- (9) The line data rate may be limited by PCS-FPGA interface speed grade.
- (10) Refer to Figure 1 for the GX channel AC gain curves. The total effective AC gain is the AC gain minus the DC gain.
- (11) t_{LTR} is the time required for the receive CDR to lock to the input reference clock frequency after coming out of reset.
- (12) t_{LTD} is time required for the receiver CDR to start recovering valid data after the rx_is_lockedtodata signal goes high.
- (13) t_{LTD_manual} is the time required for the receiver CDR to start recovering valid data after the rx_is_lockedtodata signal goes high when the CDR is functioning in the manual mode.
- (14) $t_{LTR_LTD_manual}$ is the time the receiver CDR must be kept in lock to reference (LTR) mode after the rx_is_lockedtoref signal goes high when the CDR is functioning in the manual mode.
- (15) $t_{pll_powerdown}$ is the PLL powerdown minimum pulse width.
- (16) t_{pll lock} is the time required for the transmitter CMU/ATX PLL to lock to the input reference clock frequency after coming out of reset.
- (17) To calculate the REFCLK rms phase jitter requirement for PCIe at reference clock frequencies other than 100 MHz, use the following formula: REFCLK rms phase jitter at f(MHz) = REFCLK rms phase jitter at 100 MHz × 100/f.
- (18) The maximum peak to peak differential input voltage V_{ID} after device configuration is equal to 4 × (absolute V_{MAX} for receiver pin V_{ICM}).
- (19) For ES devices, R_{BEF} is 2000 $\Omega \pm 1\%$.
- (20) To calculate the REFCLK phase noise requirement at frequencies other than 622 MHz, use the following formula: REFCLK phase noise at f(MHz) = REFCLK phase noise at 622 MHz + 20*log(f/622).
- (21) SFP/+ optical modules require the host interface to have RD+/- differentially terminated with 100 Ω. The internal OCT feature is available after the Stratix V FPGA configuration is completed. Altera recommends that FPGA configuration is completed before inserting the optical module. Otherwise, minimize unnecessary removal and insertion with unconfigured devices.
- (22) Refer to Figure 2.
- (23) For oversampling designs to support data rates less than the minimum specification, the CDR needs to be in LTR mode only.
- (24) I3YY devices can achieve data rates up to 10.3125 Gbps.
- (25) When you use fPLL as a TXPLL of the transceiver.
- (26) REFCLK performance requires to meet transmitter REFCLK phase noise specification.
- (27) Minimum eye opening of 85 mV is only for the unstressed input eye condition.

⁽¹⁾ Speed grades shown in Table 23 refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the Stratix V Device Overview.

Table 26 shows the approximate maximum data rate using the 10G PCS.

Mada (2)	Transceiver	PMA Width	64	40	40	40	32	32
mode ""	Speed Grade	PCS Width	64	66/67	50	40	64/66/67	32
	1	C1, C2, C2L, I2, I2L core speed grade	14.1	14.1	10.69	14.1	13.6	13.6
	2	C1, C2, C2L, I2, I2L core speed grade	12.5	12.5	10.69	12.5	12.5	12.5
	Z	C3, I3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88
FIFO or Register		C1, C2, C2L, I2, I2L core speed grade						
	3	C3, I3, I3L core speed grade			8.5	Gbps		
	5	C4, I4 core speed grade						
		I3YY core speed grade			10.312	25 Gbps		

Notes to Table 26:

(1) The maximum data rate is in Gbps.

(2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

Symbol/	Conditions	s	Transceive peed Grade	r 2	S	Transceive peed Grade	r 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	
Reference Clock								1
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCN	IL, 1.4-V PC	ML, 1.5-V P(CML, 2.5-V I and HCSL	PCML, Diffe	rential LVPE	ECL, LVDS,
otanuarus	RX reference clock pin		1.4-V PCML	., 1.5-V PCM	IL, 2.5-V PC	ML, LVPEC	L, and LVDS	6
Input Reference Clock Frequency (CMU PLL) ⁽⁶⁾	_	40	_	710	40	_	710	MHz
Input Reference Clock Frequency (ATX PLL) ⁽⁶⁾	_	100	_	710	100	_	710	MHz
Rise time	20% to 80%	_		400	_	_	400	
Fall time	80% to 20%			400	—	_	400	ps
Duty cycle	—	45	_	55	45	_	55	%
Spread-spectrum modulating clock frequency	PCI Express (PCIe)	30	_	33	30	_	33	kHz
Spread-spectrum downspread	PCle	_	0 to -0.5	_	_	0 to -0.5	_	%
On-chip termination resistors ⁽¹⁹⁾	_	_	100	_	_	100	_	Ω
Absolute V _{MAX} ⁽³⁾	Dedicated reference clock pin	_	_	1.6	_	_	1.6	V
	RX reference clock pin	_	_	1.2	_	_	1.2	
Absolute V _{MIN}	—	-0.4		—	-0.4	—		V
Peak-to-peak differential input voltage	_	200	_	1600	200	_	1600	mV
V _{ICM} (AC coupled)	Dedicated reference clock pin		1050/1000 ^{(,}	2)	1	050/1000 (2)	mV
	RX reference clock pin	1	.0/0.9/0.85 (22)	1.	0/0.9/0.85 ((22)	V
V _{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	_	550	250		550	mV

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 1 of 5)⁽¹⁾

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 2 of 5)⁽¹⁾

Symbol/	Conditions	S	Transceive peed Grade	r 2	SI	Fransceive Deed Grade	r 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	
	100 Hz	—	—	-70			-70	
Transmitter REFCLK	1 kHz		_	-90	_	_	-90	
Phase Noise (622	10 kHz		—	-100	_		-100	dBc/Hz
MHz) ⁽¹⁸⁾	100 kHz			-110			-110	
	\geq 1 MHz	—	—	-120	_	_	-120	
Transmitter REFCLK Phase Jitter (100 MHz) ⁽¹⁵⁾	10 kHz to 1.5 MHz (PCle)	_	_	3		_	3	ps (rms)
RREF ⁽¹⁷⁾	_	_	1800 ± 1%	—	_	1800 ± 1%	_	Ω
Transceiver Clocks								
fixedclk clock frequency	PCIe Receiver Detect	_	100 or 125	_	_	100 or 125	_	MHz
Reconfiguration clock (mgmt_clk_clk) frequency	_	100	_	125	100	_	125	MHz
Receiver	•							
Supported I/O Standards	_		1.4-V PCML	., 1.5-V PCMI	L, 2.5-V PCI	VIL, LVPEC	L, and LVDS	6
Data rate (Standard PCS) ⁽²¹⁾	GX channels	600	_	8500	600	_	8500	Mbps
Data rate (10G PCS) ⁽²¹⁾	GX channels	600	_	12,500	600	_	12,500	Mbps
Data rate	GT channels	19,600	—	28,050	19,600		25,780	Mbps
Absolute V _{MAX} for a receiver pin ⁽³⁾	GT channels	_	_	1.2	_	_	1.2	V
Absolute V _{MIN} for a receiver pin	GT channels	-0.4	_	—	-0.4	_	_	V
Maximum peak-to-peak	GT channels	_		1.6	—	_	1.6	V
differential input voltage V _{ID} (diff p-p) before device configuration ⁽²⁰⁾	GX channels				(8)			
	GT channels							
Maximum peak-to-peak differential input voltage V_{ID} (diff p-p) after device	V _{CCR_GTB} = 1.05 V (V _{ICM} = 0.65 V)	_	_	2.2	_	_	2.2	V
	GX channels		1	1 1	(8)			1
Minimum differential	GT channels	200	_	—	200		_	mV
eye opening at receiver serial input pins ⁽⁴⁾ , ⁽²⁰⁾	GX channels			·	(8)			

Symbol/	Conditions	S	Transceive peed Grade	2	S	Fransceive Deed Grade	r 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	
Differential on-chip termination resistors ⁽⁷⁾	GT channels		100	_	_	100	_	Ω
	85- Ω setting	_	85 ± 30%	_	_	85 ± 30%	_	Ω
Differential on-chip	100-Ω setting	_	100 ± 30%	_	_	100 ± 30%	_	Ω
for GX channels ⁽¹⁹⁾	120-Ω setting	_	120 ± 30%	_	—	120 ± 30%	—	Ω
	150-Ω setting	_	150 ± 30%	_	_	150 ± 30%	_	Ω
V _{ICM} (AC coupled)	GT channels	_	650	_	—	650	—	mV
	VCCR_GXB = 0.85 V or 0.9 V	_	600	_	_	600	_	mV
VICM (AC and DC coupled) for GX Channels	VCCR_GXB = 1.0 V full bandwidth	_	700		_	700	_	mV
	VCCR_GXB = 1.0 V half bandwidth	_	750	_	_	750	_	mV
t _{LTR} ⁽⁹⁾	—	_	—	10	—	—	10	μs
t _{LTD} ⁽¹⁰⁾		4			4	_	_	μs
t _{LTD_manual} ⁽¹¹⁾		4	_		4	_	_	μs
t _{LTR_LTD_manual} ⁽¹²⁾	—	15	—	_	15	—	—	μs
Run Lenath	GT channels		—	72	—	—	72	CID
	GX channels				(8)			
CDR PPM	GT channels	_	—	1000	—	—	1000	± PPM
	GX channels				(8)			
Programmable	GT channels	_		14		_	14	dB
(AC Gain) ⁽⁵⁾	GX channels				(8)			
Programmable	GT channels	_		7.5	_		7.5	dB
DC gain ⁽⁶⁾	GX channels				(8)			
Differential on-chip termination resistors ⁽⁷⁾	GT channels	_	100	—	_	100	_	Ω
Transmitter								
Supported I/O Standards	_			1.4-V	and 1.5-V P	CML		
Data rate (Standard PCS)	GX channels	600	_	8500	600		8500	Mbps
Data rate (10G PCS)	GX channels	600		12,500	600		12,500	Mbps

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 3 of 5)⁽¹⁾

Table 29 shows the V_{OD} settings for the GT channel.

Symbol	V _{OD} Setting	V _{od} Value (mV)
	0	0
	1	200
V., differential neak to neak typical (1)	2	400
The second s	3	600
	4	800
	5	1000

Note:

(1) Refer to Figure 4.

Figure 4 shows the differential transmitter output waveform.





Figure 5 shows the Stratix V AC gain curves for GT channels.

Figure 5. AC Gain Curves for GT Channels

PLL Specifications

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to 85° C) and the industrial junction temperature range (-40° to 100° C).

Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)

Symbol	Parameter	Min	Тур	Max	Unit
	Input clock frequency (C1, C2, C2L, I2, and I2L speed grades)	5		800 (1)	MHz
f _{IN}	Input clock frequency (C3, I3, I3L, and I3YY speed grades)	5		800 (1)	MHz
	Input clock frequency (C4, I4 speed grades)	5	—	650 ⁽¹⁾	MHz
f _{INPFD}	Input frequency to the PFD	5	—	325	MHz
f _{FINPFD}	Fractional Input clock frequency to the PFD	50	—	160	MHz
	PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades)	600	_	1600	MHz
f _{VCO} (9)	PLL VCO operating range (C3, I3, I3L, I3YY speed grades)	600		1600	MHz
	PLL VCO operating range (C4, I4 speed grades)	600	—	1300	MHz
t _{einduty}	Input clock or external feedback clock input duty cycle	40	—	60	%
	Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades)	_	_	717 ⁽²⁾	MHz
f _{OUT}	Output frequency for an internal global or regional clock (C3, I3, I3L speed grades)			650 ⁽²⁾	MHz
	Output frequency for an internal global or regional clock (C4, I4 speed grades)			580 ⁽²⁾	MHz
	Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades)			800 ⁽²⁾	MHz
f _{OUT_EXT}	Output frequency for an external clock output (C3, I3, I3L speed grades)			667 ⁽²⁾	MHz
	Output frequency for an external clock output (C4, I4 speed grades)			553 ⁽²⁾	MHz
t _{outduty}	Duty cycle for a dedicated external clock output (when set to 50%)	45	50	55	%
t _{FCOMP}	External feedback clock compensation time	_		10	ns
f _{dyconfigclk}	Dynamic Configuration Clock used for mgmt_clk and scanclk		_	100	MHz
t _{LOCK}	Time required to lock from the end-of-device configuration or deassertion of areset			1	ms
t _{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)			1	ms
	PLL closed-loop low bandwidth	—	0.3	—	MHz
f _{CLBW}	PLL closed-loop medium bandwidth	—	1.5	—	MHz
	PLL closed-loop high bandwidth (7)	—	4	-	MHz
t _{PLL_PSERR}	Accuracy of PLL phase shift	—	—	±50	ps
t _{ARESET}	Minimum pulse width on the areset signal	10	—	_	ns

Symbol	Parameter	Min	Тур	Max	Unit
+ (3) (4)	Input clock cycle-to-cycle jitter ($f_{REF} \ge 100 \text{ MHz}$)			0.15	UI (p-p)
LINCCJ (0), (1)	Input clock cycle-to-cycle jitter (f _{REF} < 100 MHz)	-750		+750	ps (p-p)
+ (5)	Period Jitter for dedicated clock output (f_{OUT} \geq 100 MHz)	_	_	175 ⁽¹⁾	ps (p-p)
CUTPJ_DC	Period Jitter for dedicated clock output (f _{OUT} < 100 MHz)	_	_	17.5 ⁽¹⁾	mUI (p-p)
+ (5)	Period Jitter for dedicated clock output in fractional PLL ($f_{OUT} \ge 100 \text{ MHz}$)	_	_	250 ⁽¹¹⁾ , 175 ⁽¹²⁾	ps (p-p)
FOUTPJ_DC	Period Jitter for dedicated clock output in fractional PLL (f _{OUT} < 100 MHz)	_	_	25 ⁽¹¹⁾ , 17.5 ⁽¹²⁾	mUI (p-p)
+ (5)	Cycle-to-Cycle Jitter for a dedicated clock output ($f_{\text{OUT}} \geq 100 \text{ MHz})$		_	175	ps (p-p)
COUTCCJ_DC	Cycle-to-Cycle Jitter for a dedicated clock output $(f_{OUT} < 100 \text{ MHz})$		_	17.5	mUI (p-p)
+ (5)	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{OUT} \ge 100 \text{ MHz}$)		_	250 ⁽¹¹⁾ , 175 ⁽¹²⁾	ps (p-p)
FOUTCCJ_DC	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{OUT} < 100 \text{ MHz}$)+		_	25 ⁽¹¹⁾ , 17.5 ⁽¹²⁾	mUI (p-p)
t _{outpj 10} (5),	Period Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} \ge 100 \text{ MHz}$)		_	600	ps (p-p)
(8)	Period Jitter for a clock output on a regular I/O $(f_{OUT} < 100 \text{ MHz})$		_	60	mUI (p-p)
t _{foutpj 10} ^{(5),}	Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} \ge 100 \text{ MHz}$)	_	_	600 ⁽¹⁰⁾	ps (p-p)
(8), (11)	Period Jitter for a clock output on a regular I/O in fractional PLL (f _{OUT} < 100 MHz)	_	_	60 ⁽¹⁰⁾	mUI (p-p)
t _{outccj_io} (5),	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} \geq 100 \mbox{ MHz})$	_	_	600	ps (p-p)
(8)	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL (f _{OUT} < 100 MHz)	_	_	60 ⁽¹⁰⁾	mUI (p-p)
t _{FOUTCCJ 10} (5),	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} \ge 100$ MHz)		_	600 ⁽¹⁰⁾	ps (p-p)
(8), (11)	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL (f _{OUT} < 100 MHz)	_	_	60	mUI (p-p)
t _{CASC OUTPJ DC}	Period Jitter for a dedicated clock output in cascaded PLLs ($f_{OUT} \ge 100 \text{ MHz}$)	_	_	175	ps (p-p)
(5), (6)	Period Jitter for a dedicated clock output in cascaded PLLs (f_{OUT} < 100 MHz)	_	_	17.5	mUI (p-p)
f _{DRIFT}	Frequency drift after PFDENA is disabled for a duration of 100 μs		_	±10	%
dK _{BIT}	Bit number of Delta Sigma Modulator (DSM)	8	24	32	Bits
k _{VALUE}	Numerator of Fraction	128	8388608	2147483648	—

Table 31. PLL Specifications for Stratix V Devices (Part 2 of 3)

			F	eformanc	e			
Mode	C1	C2, C2L	12, 12L	C3	13, 13L, 13YY	C4	14	Unit
		Modes us	ing Three	DSPs				
One complex 18 x 25	425	425	415	340	340	275	265	MHz
		Modes us	sing Four	DSPs				
One complex 27 x 27	465	465	465	380	380	300	290	MHz

Table 32. Block Performance Specifications for Stratix V DSP Devices (Part 2 of 2)

Memory Block Specifications

Table 33 lists the Stratix V memory block specifications.

Table 33. Memory Block Performance Specifications for Stratix V Devices ^{(1), (2)} (Part 1 of 2)

		Resour	ces Used			Pe	erforman	ce			
Memory	Mode	ALUTS	Memory	C1	C2, C2L	C3	C4	12, 12L	13, 13L, 13YY	14	Unit
	Single port, all supported widths	0	1	450	450	400	315	450	400	315	MHz
MLAR	Simple dual-port, x32/x64 depth	0	1	450	450	400	315	450	400	315	MHz
WILAD	Simple dual-port, x16 depth ⁽³⁾	0	1	675	675	533	400	675	533	400	MHz
	ROM, all supported widths	0	1	600	600	500	450	600	500	450	MHz

Jitter Free	quency (Hz)	Sinusoidal Jitter (UI)
F1	10,000	25.000
F2	17,565	25.000
F3	1,493,000	0.350
F4	50,000,000	0.350

iadie 38. lvus sott-luk/upa sinusoidai jitter mask vaiues tor a uata kate > 1.2	25 G	.2	1.	1	>	>		Ì	e	F	Ł	đ	a	2	1	R	P							Ľ	I.		I.	Ì	1	3	a	3	a	2	2	2	ŀ	t	t	t	ſ	ľ	3	2	2	2	2	2	1)	D		I		Ľ	1	2	2	ź	â	i		۴	ŕ	r	r		I	I	Ì	1	Π	٥	٢	i	F	f	f	1	1		5	S	S	S	2	2	e	E	I	U	h	I	۱	a	ŀ	I	V	۱			ľ	٢	k	k	s	S	S	1	a	2	2		И	V	N			•	۴	r	r	1	1	1	2	2	2	2	e	e	e	E	t	t	i	ŀ	t	ľ	i	i	f	f	ŀ	ŀ	li
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Figure 9 shows the **LVDS** soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate < 1.25 Gbps.





DLL Range, DQS Logic Block, and Memory Output Clock Jitter Specifications

Table 39 lists the DLL range specification for Stratix V devices. The DLL is always in 8-tap mode in Stratix V devices.

Table 39. DLL Range Specifications for Stratix V Devices (1)

C1	C2, C2L, I2, I2L	C3, I3, I3L, I3YY	C4,I4	Unit
300-933	300-933	300-890	300-890	MHz

Note to Table 39:

(1) Stratix V devices support memory interface frequencies lower than 300 MHz, although the reference clock that feeds the DLL must be at least 300 MHz. To support interfaces below 300 MHz, multiply the reference clock feeding the DLL to ensure the frequency is within the supported range of the DLL.

Table 40 lists the DQS phase offset delay per stage for Stratix V devices.

Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices ^{(1), (2)} (Part 1 of 2)

Speed Grade	Min	Max	Unit
C1	8	14	ps
C2, C2L, I2, I2L	8	14	ps
C3,I3, I3L, I3YY	8	15	ps

FPP Configuration Timing when DCLK-to-DATA [] = 1

Figure 12 shows the timing waveform for FPP configuration when using a MAX II or MAX V device as an external host. This waveform shows timing when the DCLK-to-DATA[] ratio is 1.





Notes to Figure 12:

- (1) Use this timing waveform when the DCLK-to-DATA [] ratio is 1.
- (2) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF_DONE are at logic-high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (3) After power-up, the Stratix V device holds nstatus low for the time of the POR delay.
- (4) After power-up, before and during configuration, CONF_DONE is low.
- (5) Do not leave DCLK floating after configuration. DCLK is ignored after configuration is complete. It can toggle high or low if required.
- (6) For FPP ×16, use DATA [15..0]. For FPP ×8, use DATA [7..0]. DATA [31..0] are available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings.
- (7) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF_DONE is released high when the Stratix V device receives all the configuration data successfully. After CONF_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (8) After the option bit to enable the INIT_DONE pin is configured into the device, the INIT DONE goes low.

Table 60.	Glossary	(Part 3 of 4)
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Letter	Subject	Definitions			
	SW (sampling window)	Timing Diagram—the period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window, as shown: Bit Time 0.5 x TCCS RSKM Sampling Window RSKM 0.5 x TCCS RSKM			
S	Single-ended voltage referenced I/O standard	The JEDEC standard for SSTL and HSTL I/O defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: <i>Single-Ended Voltage Referenced I/O Standard</i> 			
	t _C	High-speed receiver and transmitter input and output clock period.			
	TCCS (channel- to-channel-skew)	The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the <i>Timing Diagram</i> figure under SW in this table).			
	touty	High-speed I/O block—Duty cycle on the high-speed transmitter output clock.			
т		Timing Unit Interval (TUI) The timing budget allowed for skew, propagation delays, and the data sampling window.			
		(TUI = 1/(receiver input clock frequency multiplication factor) = t_c/w)			
	t _{FALL}	Signal high-to-low transition time (80-20%)			
	t _{INCCJ}	Cycle-to-cycle jitter tolerance on the PLL clock input.			
	t _{outpj_i0}	Period jitter on the general purpose I/O driven by a PLL.			
	t _{outpj_dc}	Period jitter on the dedicated clock output driven by a PLL.			
	t _{RISE}	Signal low-to-high transition time (20-80%)			
U		_			

Document Revision History

Table 61 lists the revision history for this chapter.

 Table 61. Document Revision History (Part 1 of 3)

Date	Version	Changes	
June 2018	3.9	 Added the "Stratix V Device Overshoot Duration" figure. 	
April 2017	3.8	Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.	
		 Changed the minimum value for t_{CD2UMC} in the "PS Timing Parameters for Stratix V Devices" table. 	
		 Changed the condition for 100-Ω R_D in the "OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices" table. 	
		 Changed the minimum value for t_{CD2UMC} in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table 	
		 Changed the minimum value for t_{CD2UMC} in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1" table. 	
		 Changed the minimum value for t_{CD2UMC} in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1" table. 	
		 Changed the minimum number of clock cycles value in the "Initialization Clock Source Option and the Maximum Frequency" table. 	
June 2016	3.7	 Added the V_{ID} minimum specification for LVPECL in the "Differential I/O Standard Specifications for Stratix V Devices" table 	
		 Added the I_{OUT} specification to the "Absolute Maximum Ratings for Stratix V Devices" table. 	
December 2015	3.6	Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.	
December 2015	3.5	 Changed the transmitter, receiver, and ATX PLL data rate specifications in the "Transceiver Specifications for Stratix V GX and GS Devices" table. 	
		 Changed the configuration .rbf sizes in the "Uncompressed .rbf Sizes for Stratix V Devices" table. 	
	3.4	• Changed the data rate specification for transceiver speed grade 3 in the following tables:	
		 "Transceiver Specifications for Stratix V GX and GS Devices" 	
		 "Stratix V Standard PCS Approximate Maximum Date Rate" 	
		 "Stratix V 10G PCS Approximate Maximum Data Rate" 	
July 2015		 Changed the conditions for reference clock rise and fall time, and added a note to the "Transceiver Specifications for Stratix V GX and GS Devices" table. 	
		 Added a note to the "Minimum differential eye opening at receiver serial input pins" specification in the "Transceiver Specifications for Stratix V GX and GS Devices" table. 	
		 Changed the t_{c0} maximum value in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table. 	
		 Removed the CDR ppm tolerance specification from the "Transceiver Specifications for Stratix V GX and GS Devices" table. 	

 Table 61. Document Revision History (Part 3 of 3)

Date	Version	Changes
May 2013		■ Updated Table 2, Table 6, Table 7, Table 20, Table 23, Table 27, Table 47, Table 60
	2.7	Added Table 24, Table 48
		 Updated Figure 9, Figure 10, Figure 11, Figure 12
February 2013	26	 Updated Table 7, Table 9, Table 20, Table 23, Table 27, Table 30, Table 31, Table 35, Table 46
		Updated "Maximum Allowed Overshoot and Undershoot Voltage"
		 Updated Table 3, Table 6, Table 7, Table 8, Table 23, Table 24, Table 25, Table 27, Table 30, Table 32, Table 35
		Added Table 33
	2.5	 Added "Fast Passive Parallel Configuration Timing"
		 Added "Active Serial Configuration Timing"
December 2012		 Added "Passive Serial Configuration Timing"
		 Added "Remote System Upgrades"
		 Added "User Watchdog Internal Circuitry Timing Specification"
		Added "Initialization"
		Added "Raw Binary File Size"
June 2012	2.4	 Added Figure 1, Figure 2, and Figure 3.
		 Updated Table 1, Table 2, Table 3, Table 6, Table 11, Table 22, Table 23, Table 27, Table 29, Table 30, Table 31, Table 32, Table 35, Table 38, Table 39, Table 40, Table 41, Table 43, Table 56, and Table 59.
		 Various edits throughout to fix bugs.
		Changed title of document to <i>Stratix V Device Datasheet</i> .
		 Removed document from the Stratix V handbook and made it a separate document.
February 2012	2.3	■ Updated Table 1–22, Table 1–29, Table 1–31, and Table 1–31.
December 2011	2.2	■ Added Table 2–31.
December 2011		■ Updated Table 2–28 and Table 2–34.
November 2011	2.1	 Added Table 2–2 and Table 2–21 and updated Table 2–5 with information about Stratix V GT devices.
		 Updated Table 2–11, Table 2–13, Table 2–20, and Table 2–25.
		 Various edits throughout to fix SPRs.
May 2011	2.0	■ Updated Table 2–4, Table 2–18, Table 2–19, Table 2–21, Table 2–22, Table 2–23, and Table 2–24.
		 Updated the "DQ Logic Block and Memory Output Clock Jitter Specifications" title.
		Chapter moved to Volume 1.
		 Minor text edits.
December 2010	1.1	■ Updated Table 1–2, Table 1–4, Table 1–19, and Table 1–23.
		 Converted chapter to the new template.
		 Minor text edits.
July 2010	1.0	Initial release.